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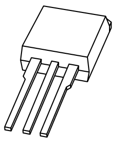


BUK7E07-55B

N-channel TrenchMOS standard level FET

Rev. 01 — 29 January 2008 **Product data sheet**

1. Product profile

1.1 General description

N-channel enhancement mode power Field-Effect Transistor (FET) in a plastic package using NXP High-Performance Automotive (HPA) TrenchMOS technology. This product has been designed and qualified to the appropriate AEC standard for use in Automotive critical applications.

1.2 Features

- Very low on-state resistance
- 175 °C rated
- Q101 compliant
- Standard level compatible

1.3 Applications

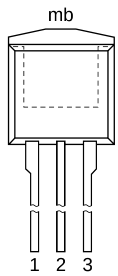
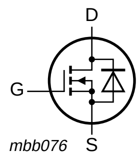
- Automotive systems
- Motors, lamps and solenoids
- General purpose power switching
- 12 V and 24 V loads

1.4 Quick reference data

- $E_{DS(AL)S} \leq 351$ mJ
- $I_D \leq 75$ A
- $R_{DSon} = 5.8$ mΩ (typ)
- $P_{tot} \leq 203$ W

2. Pinning information

Table 1. Pinning

Pin	Description	Simplified outline	Symbol
1	gate (G)		
2	drain (D)		
3	source (S)		
mb	mounting base; connected to drain (D)	SOT226 (I2PAK)	

founded by Philips

3. Ordering information

Table 2. Ordering information

Type number	Package		
	Name	Description	Version
BUK7E07-55B	I2PAK	plastic single-ended package (I2PAK); low-profile 3-lead TO-220AB	SOT226

4. Limiting values

Table 3. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions		Min	Max	Unit
V_{DS}	drain-source voltage			-	55	V
V_{DGR}	drain-gate voltage (DC)	R_{GS} = 20 kΩ		-	55	V
V_{GS}	gate-source voltage			-	±20	V
I_D	drain current	T_{mb} = 25 °C; V_{GS} = 10 V; see Figure 2 and 3	[1]	-	119	A
			[2]		75	A
		T_{mb} = 100 °C; V_{GS} = 10 V; see Figure 2	[2]	-	75	A
I_{DM}	peak drain current	T_{mb} = 25 °C; pulsed; $t_p \leq$ 10 µs; see Figure 3		-	478	A
P_{tot}	total power dissipation	T_{mb} = 25 °C; see Figure 1		-	203	W
T_{stg}	storage temperature			–55	+175	°C
T_j	junction temperature			–55	+175	°C
Source-drain diode						
I_{DR}	reverse drain current	T_{mb} = 25 °C	[2]	-	75	A
I_{DRM}	peak reverse drain current	T_{mb} = 25 °C; pulsed; $t_p \leq$ 10 µs		-	478	A
Avalanche ruggedness						
$E_{DS(AL)S}$	non-repetitive drain-source avalanche energy	Unclamped inductive load; I_D = 75 A; $V_{DS} \leq$ 55 V; V_{GS} = 10 V; R_{GS} = 50 Ω; starting at T_j = 25 °C		-	351	mJ
$E_{DS(AL)R}$	repetitive drain-source avalanche energy	Repetitive rating defined in Figure 16	[3]	-	-	J

[1] Current is limited by chip power dissipation rating.

[2] Continuous current is limited by package.

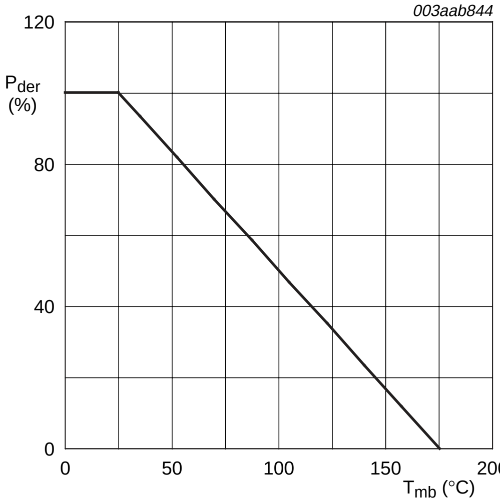
[3] Conditions:

a) Maximum value not quoted.

b) Single-pulse avalanche rating limited by $T_{j(max)}$ of 175 °C.

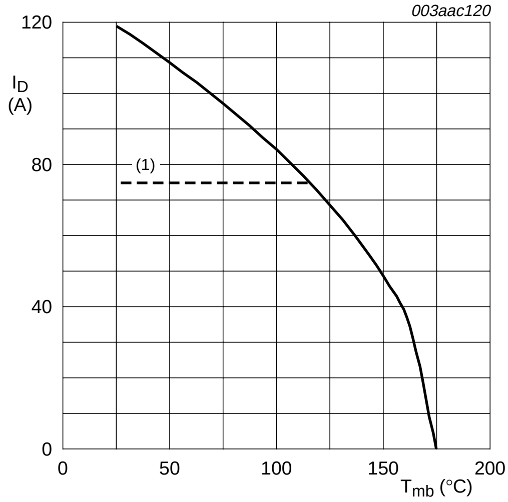
c) Repetitive avalanche rating limited by an average junction temperature of 170 °C.

d) Refer to application note *AN10273* for further information.



$$P_{der} = \frac{P_{tot}}{P_{tot(25^{\circ}C)}} \times 100\ \%$$

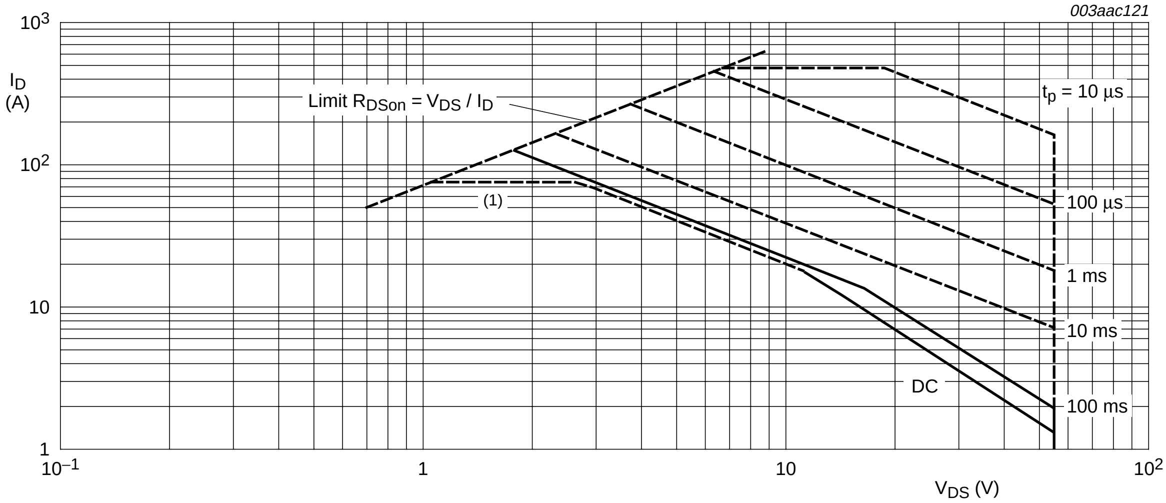
Fig 1. Normalized total power dissipation as a function of mounting base temperature



$V_{GS} \geq 10$ V

(1) Capped at 75 A due to package.

Fig 2. Continuous drain current as a function of mounting base temperature



$T_{mb} = 25$ °C; I_{DM} is single pulse.

(1) Capped at 75 A due to package.

Fig 3. Safe operating area; continuous and peak drain currents as a function of drain-source voltage

5. Thermal characteristics

Table 4. Thermal characteristics

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
$R_{th(j-mb)}$	thermal resistance from junction to mounting base	-	-	-	0.74	K/W
$R_{th(j-a)}$	thermal resistance from junction to ambient	vertical in still air	-	60	-	K/W

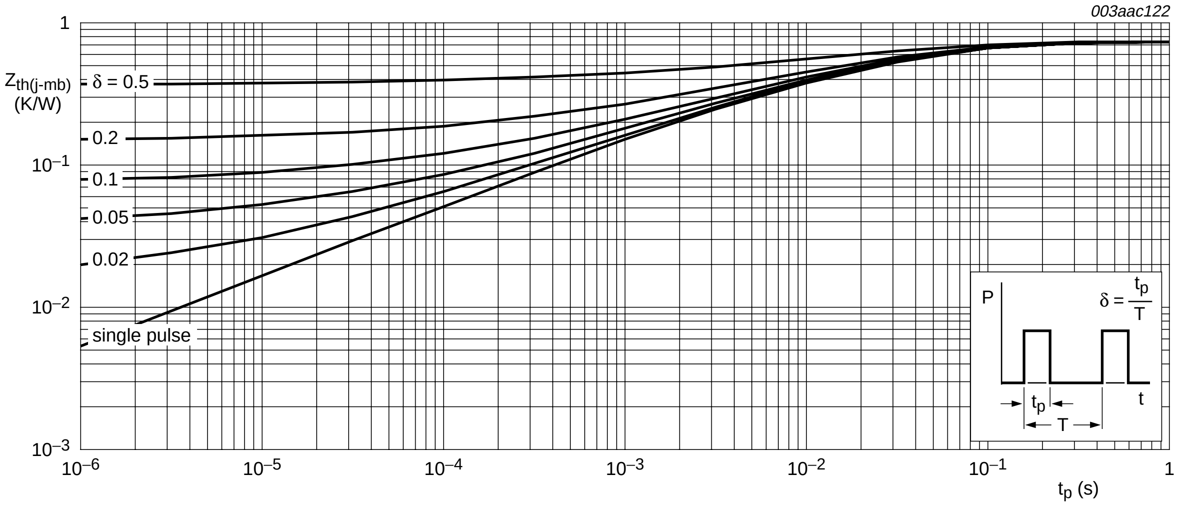


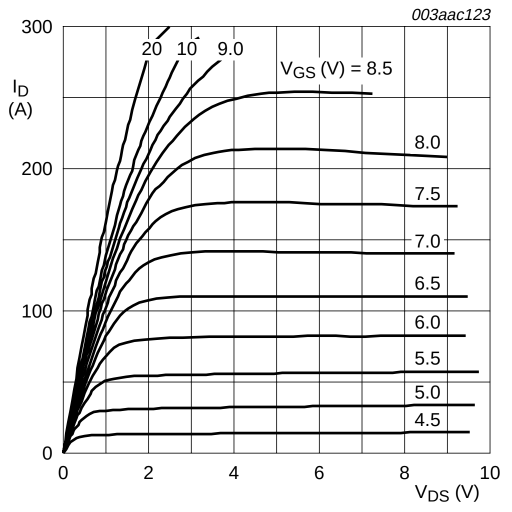
Fig 4. Transient thermal impedance from junction to mounting base as a function of pulse duration

6. Characteristics

Table 5. Characteristics

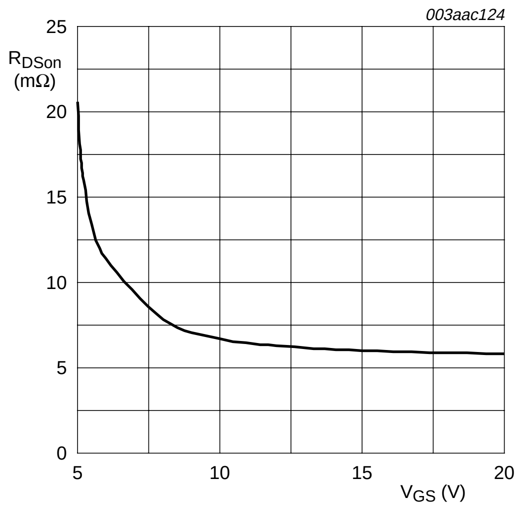
T_j = 25 °C unless otherwise specified.

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
Static characteristics						
$V_{(BR)DSS}$	drain-source breakdown voltage	I_D = 0.25 mA; V_{GS} = 0 V				
		T_j = 25 °C	55	-	-	V
		T_j = –55 °C	50	-	-	V
$V_{GS(th)}$	gate-source threshold voltage	I_D = 1 mA; V_{DS} = V_{GS}; see Figure 9 and 10				
		T_j = 25 °C	2	3	4	V
		T_j = 175 °C	1	-	-	V
		T_j = –55 °C	-	-	4.4	V
I_{DSS}	drain leakage current	V_{DS} = 55 V; V_{GS} = 0 V				
		T_j = 25 °C	-	0.02	1	µA
		T_j = 175 °C	-	-	500	µA
I_{GSS}	gate leakage current	V_{GS} = ±20 V; V_{DS} = 0 V	-	2	100	nA
R_{DSon}	drain-source on-state resistance	V_{GS} = 10 V; I_D = 25 A; see Figure 6 and 8				
		T_j = 25 °C	-	5.8	7.1	mΩ
		T_j = 175 °C	-	-	14.2	mΩ
Dynamic characteristics						
$Q_{G(tot)}$	total gate charge	I_D = 25 A; V_{DS} = 44 V; V_{GS} = 10 V; see Figure 14	-	53	-	nC
Q_{GS}	gate-source charge		-	12	-	nC
Q_{GD}	gate-drain charge		-	17	-	nC
C_{iss}	input capacitance	V_{GS} = 0 V; V_{DS} = 25 V; f = 1 MHz; see Figure 12	-	2820	3760	pF
C_{oss}	output capacitance		-	554	665	pF
C_{rss}	reverse transfer capacitance		-	200	274	pF
$t_{d(on)}$	turn-on delay time	V_{DS} = 30 V; R_L = 1.2 Ω; V_{GS} = 10 V; R_G = 10 Ω	-	24	-	ns
t_r	rise time		-	52	-	ns
$t_{d(off)}$	turn-off delay time		-	77	-	ns
t_f	fall time		-	41	-	ns
L_D	internal drain inductance	measured from drain lead 6 mm from package to centre of die	-	4.5	-	nH
L_S	internal source inductance	measured from source lead to source bond pad	-	7.5	-	nH
Source-drain diode						
V_{SD}	source-drain voltage	I_S = 25 A; V_{GS} = 0 V; see Figure 15	-	0.85	1.2	V
t_{rr}	reverse recovery time	I_S = 20 A; dI_S/dt = –100 A/µs; V_{GS} = 0 V; V_R = 30 V	-	62	-	ns
Q_r	recovered charge		-	60	-	nC



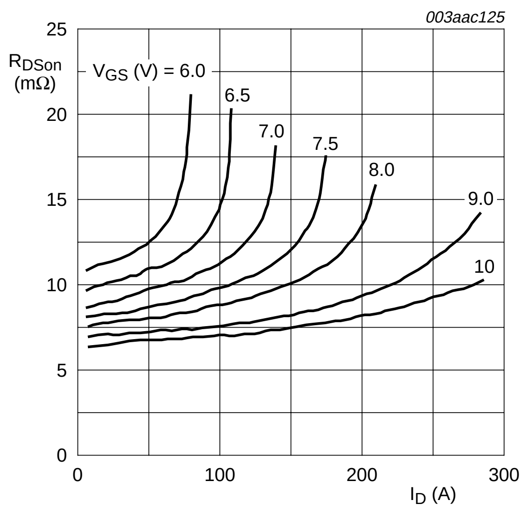
T_j = 25 °C

Fig 5. Output characteristics: drain current as a function of drain-source voltage; typical values



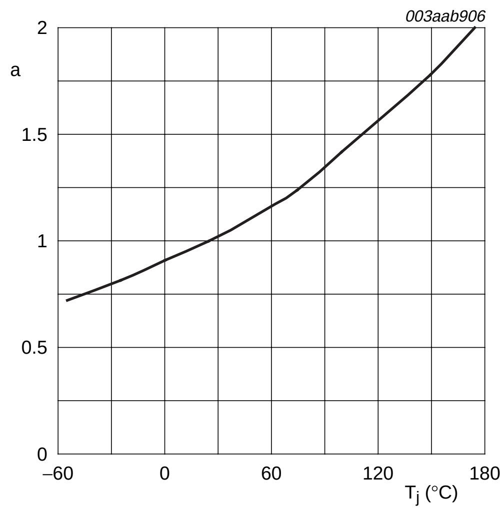
T_j = 25 °C; I_D = 25 A

Fig 6. Drain-source on-state resistance as a function of gate-source voltage; typical values



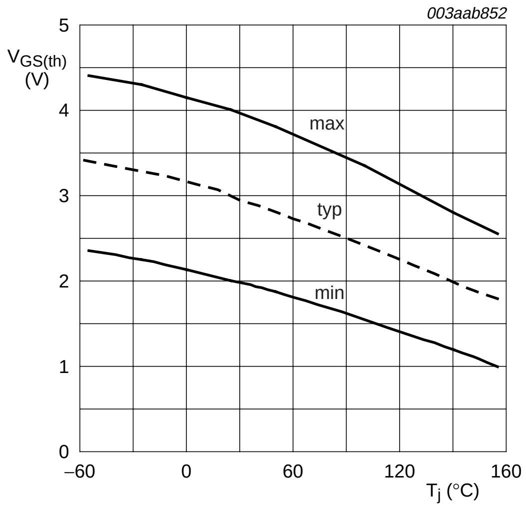
T_j = 25 °C

Fig 7. Drain-source on-state resistance as a function of drain current; typical values



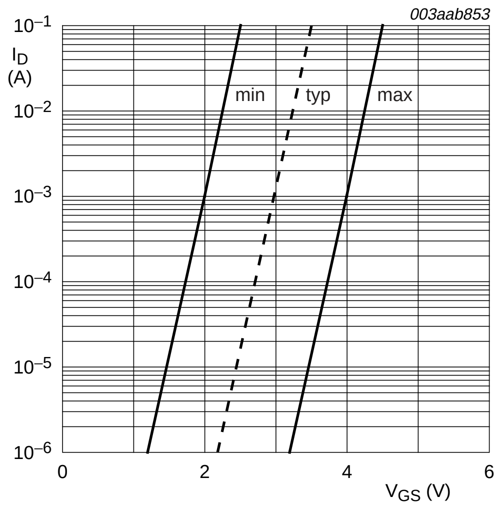
$$a = \frac{R_{DSon}}{R_{DSon(25°C)}}$$

Fig 8. Normalized drain-source on-state resistance factor as a function of junction temperature



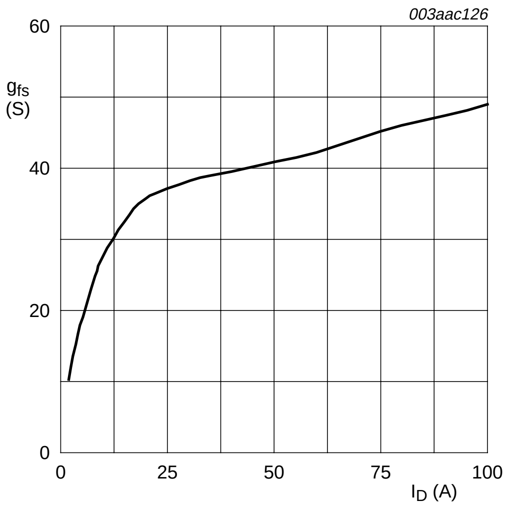
I_D = 1 mA; $V_{DS} = V_{GS}$

Fig 9. Gate-source threshold voltage as a function of junction temperature



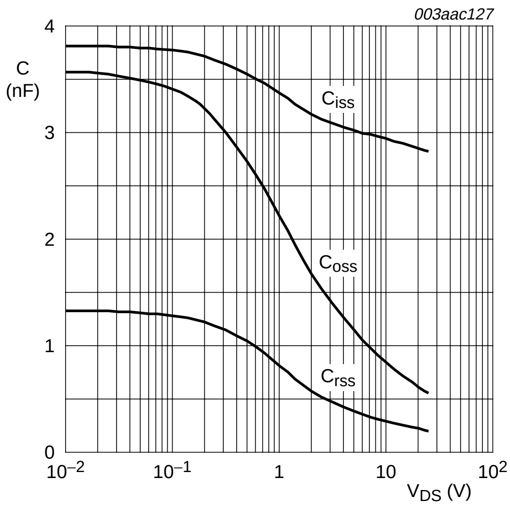
T_j = 25 °C; $V_{DS} = V_{GS}$

Fig 10. Sub-threshold drain current as a function of gate-source voltage



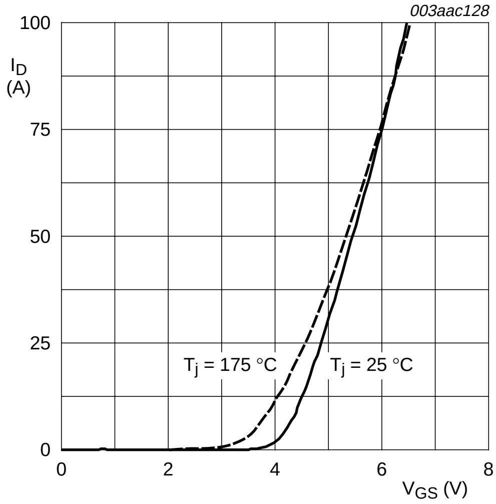
T_j = 25 °C; V_{DS} = 25 V

Fig 11. Forward transconductance as a function of drain current; typical values



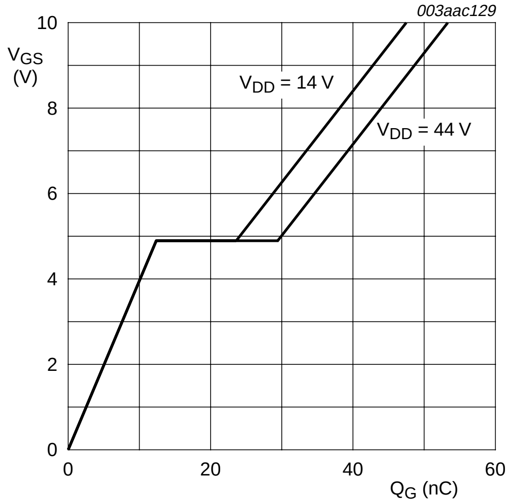
V_{GS} = 0 V; f = 1 MHz

Fig 12. Input, output and reverse transfer capacitances as a function of drain-source voltage; typical values



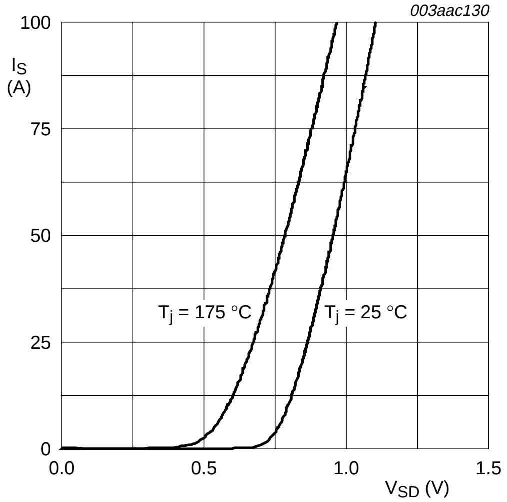
V_{DS} = 25 V

Fig 13. Transfer characteristics: drain current as a function of gate-source voltage; typical values



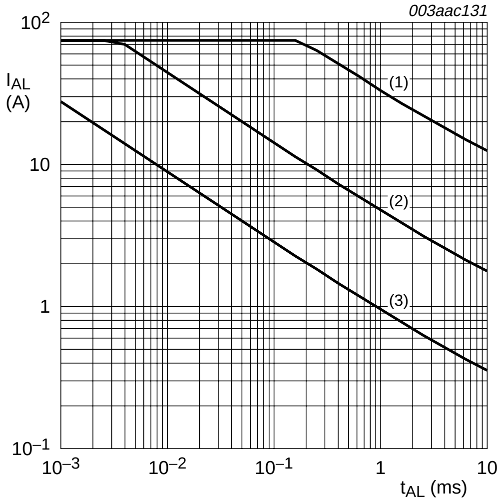
T_j = 25 °C; I_D = 25 A

Fig 14. Gate-source voltage as a function of gate charge; typical values



V_{GS} = 0 V

Fig 15. Source (diode forward) current as a function of source-drain (diode forward) voltage; typical values



See Table note 3 of Table 3 Limiting values.

(1) Single-pulse; T_j = 25 °C.

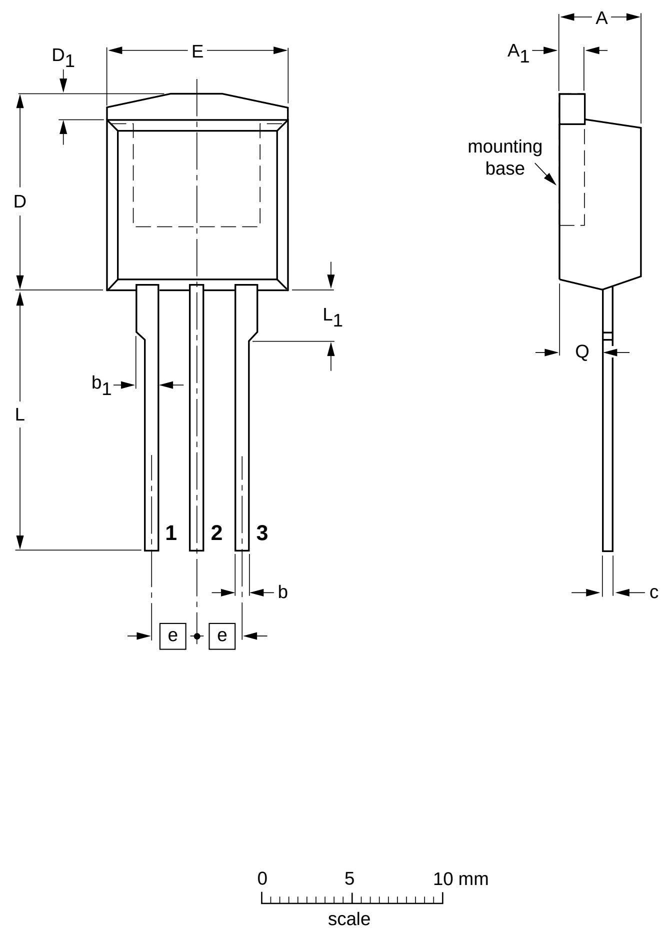
(2) Single-pulse; T_j = 150 °C.

(3) Repetitive.

Fig 16. Single-pulse and repetitive avalanche rating; avalanche current as a function of avalanche time

7. Package outline

Plastic single-ended package (I2PAK); low-profile 3-lead TO-220AB **SOT226**



DIMENSIONS (mm are the original dimensions)

UNIT	A	A_1	b	b_1	c	D max	D_1	E	e	L	L_1	Q
mm	4.5 4.1	1.40 1.27	0.85 0.60	1.3 1.0	0.7 0.4	11	1.6 1.2	10.3 9.7	2.54	15.0 13.5	3.30 2.79	2.6 2.2

OUTLINE VERSION	REFERENCES				EUROPEAN PROJECTION	ISSUE DATE
	IEC	JEDEC	JEITA			
SOT226		low-profile 3-lead TO-220AB				~~05-06-23~~ 06-02-14

Fig 17. Package outline SOT226 (I2PAK)

8. Revision history

Table 6. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes
BUK7E07-55B_1	20080129	Product data	-	-

9. Legal information

9.1 Data sheet status

Document status[1][2]	Product status[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

[1] Please consult the most recently issued document before initiating or completing a design.

[2] The term 'short data sheet' is explained in section "Definitions".

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11. Contents

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